

Notice of References Cited	Application/Control No. 10/085,226	Applicant(s)/Patent Under Reexamination PARRISH ET AL.	
	Examiner Christine Sung	Art Unit 2878	Page 1 of 1

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NON-PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

U.S. Department of Commerce, Patent and Trademark Office					Atty Docket No.		Serial No.	
					M-15240 US		Not Yet Assigned	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT					Applicant(s)			
(Use several sheets if necessary)					William J. Parrish et al.			
					Filing Date		Group	
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